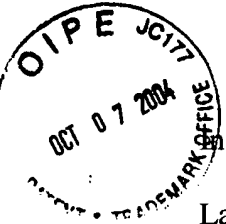


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PATENT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

## ~~En~~ re Application of

Lawrence C. LEI et al.

Serial No. 10/685,210

: Group Art Unit: 2858

Filed: October 14, 2003

: Examiner:

For: METHOD AND APPARATUS FOR MEASURING OBJECT THICKNESS

## TRANSMITTAL OF FORMAL DRAWINGS

Honorable Commissioner for Patents  
Alexandria, VA 22313-1450

Sir:

At the time the above application was filed, informal drawings were presented with the application. The formal drawings are submitted herewith.

Respectfully submitted,

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